



Welcome to **E-XFL.COM**

Understanding <u>Embedded - FPGAs (Field Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	100
Number of Logic Elements/Cells	238
Total RAM Bits	3200
Number of I/O	77
Number of Gates	5000
Voltage - Supply	3V ~ 3.6V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	100-TQFP
Supplier Device Package	100-VQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcs05xl-4vqg100c

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



The register choice is made by placing the appropriate library symbol. For example, IFD is the basic input flip-flop (rising edge triggered), and ILD is the basic input latch (transparent-High). Variations with inverted clocks are also available. The clock signal inverter is also shown in Figure 5 on the CK line.

The Spartan family IOB data input path has a one-tap delay element: either the delay is inserted (default), or it is not. The Spartan-XL family IOB data input path has a two-tap delay element, with choices of a full delay, a partial delay, or no delay. The added delay guarantees a zero hold time with respect to clocks routed through the global clock buffers. (See Global Nets and Buffers, page 12 for a description of the global clock buffers in the Spartan/XL families.) For a shorter input register setup time, with positive hold-time, attach a NODELAY attribute or property to the flip-flop. The output of the input register goes to the routing channels (via I1 and I2 in Figure 6). The I1 and I2 signals that exit the IOB can each carry either the direct or registered input signal.

The 5V Spartan family input buffers can be globally configured for either TTL (1.2V) or CMOS (VCC/2) thresholds,

using an option in the bitstream generation software. The Spartan family output levels are also configurable; the two global adjustments of input threshold and output level are independent. The inputs of Spartan devices can be driven by the outputs of any 3.3V device, if the Spartan family inputs are in TTL mode. Input and output thresholds are TTL on all configuration pins until the configuration has been loaded into the device and specifies how they are to be used. Spartan-XL family inputs are TTL compatible and 3.3V CMOS compatible.

Supported sources for Spartan/XL device inputs are shown in Table 4.

Spartan-XL family I/Os are fully 5V tolerant even though the V_{CC} is 3.3V. This allows 5V signals to directly connect to the Spartan-XL family inputs without damage, as shown in Table 4. In addition, the 3.3V V_{CC} can be applied before or after 5V signals are applied to the I/Os. This makes the Spartan-XL devices immune to power supply sequencing problems.

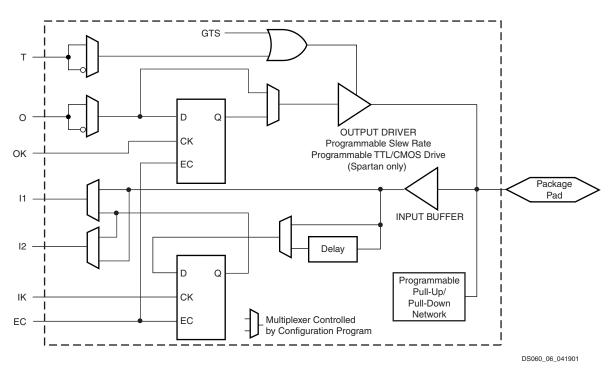


Figure 6: Simplified Spartan/XL IOB Block Diagram



- The 16 x 1 single-port configuration contains a RAM array with 16 locations, each one-bit wide. One 4-bit address decoder determines the RAM location for write and read operations. There is one input for writing data and one output for reading data, all at the selected address.
- The (16 x 1) x 2 single-port configuration combines two 16 x 1 single-port configurations (each according to the preceding description). There is one data input, one data output and one address decoder for each array. These arrays can be addressed independently.
- The 32 x 1 single-port configuration contains a RAM array with 32 locations, each one-bit wide. There is one data input, one data output, and one 5-bit address decoder.
- The dual-port mode 16 x 1 configuration contains a RAM array with 16 locations, each one-bit wide. There are two 4-bit address decoders, one for each port. One port consists of an input for writing and an output for reading, all at a selected address. The other port consists of one output for reading from an independently selected address.

The appropriate choice of RAM configuration mode for a given design should be based on timing and resource requirements, desired functionality, and the simplicity of the design process. Selection criteria include the following: Whereas the 32 x 1 single-port, the (16 x 1) x 2 single-port, and the 16 x 1 dual-port configurations each use one entire CLB, the 16 x 1 single-port configuration uses only one half of a CLB. Due to its simultaneous read/write capability, the dual-port RAM can transfer twice as much data as the single-port RAM, which permits only one data operation at any given time.

CLB memory configuration options are selected by using the appropriate library symbol in the design entry.

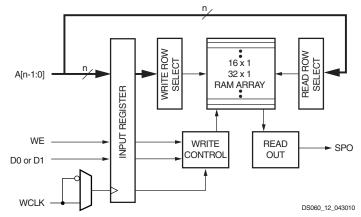
Single-Port Mode

There are three CLB memory configurations for the single-port RAM: 16×1 , $(16 \times 1) \times 2$, and 32×1 , the functional organization of which is shown in Figure 12.

The single-port RAM signals and the CLB signals (Figure 2, page 4) from which they are originally derived are shown in Table 9.

Table 9: Single-Port RAM Signals

RAM Signal	Function	CLB Signal
D0 or D1	Data In	DIN or H1
A[3:0]	Address	F[4:1] or G[4:1]
A4 (32 x 1 only)	Address	H1
WE	Write Enable	SR
WCLK	Clock	К
SPO	Single Port Out (Data Out)	F _{OUT} or G _{OUT}



Notes:

- The (16 x 1) x 2 configuration combines two 16 x 1 single-port RAMs, each with its own independent address bus and data input. The same WE and WCLK signals are connected to both RAMs.
- 2. n = 4 for the 16 x 1 and (16 x 1) x 2 configurations. n = 5 for the 32 x 1 configuration.

Figure 12: Logic Diagram for the Single-Port RAM

Writing data to the single-port RAM is essentially the same as writing to a data register. It is an edge-triggered (synchronous) operation performed by applying an address to the A inputs and data to the D input during the active edge of WCLK while WE is High.

The timing relationships are shown in Figure 13. The High logic level on WE enables the input data register for writing. The active edge of WCLK latches the address, input data, and WE signals. Then, an internal write pulse is generated that loads the data into the memory cell.



CLB signals from which they are originally derived are shown in Table 10.

Table 10: Dual-Port RAM Signals

RAM Signal	Function	CLB Signal
D	Data In	DIN
A[3:0]	Read Address for Single-Port.	F[4:1]
	Write Address for Single-Port and Dual-Port.	
DPRA[3:0]	Read Address for Dual-Port	G[4:1]
WE	Write Enable	SR
WCLK	Clock	К
SPO	Single Port Out (addressed by A[3:0])	F _{OUT}
DPO	Dual Port Out (addressed by DPRA[3:0])	G _{OUT}

The RAM16X1D primitive used to instantiate the dual-port RAM consists of an upper and a lower 16 x 1 memory array. The address port labeled A[3:0] supplies both the read and write addresses for the lower memory array, which behaves the same as the 16 x 1 single-port RAM array described previously. Single Port Out (SPO) serves as the data output for the lower memory. Therefore, SPO reflects the data at address A[3:0].

The other address port, labeled DPRA[3:0] for Dual Port Read Address, supplies the read address for the upper memory. The write address for this memory, however, comes from the address A[3:0]. Dual Port Out (DPO) serves as the data output for the upper memory. Therefore, DPO reflects the data at address DPRA[3:0].

By using A[3:0] for the write address and DPRA[3:0] for the read address, and reading only the DPO output, a FIFO that can read and write simultaneously is easily generated. The simultaneous read/write capability possible with the dual-port RAM can provide twice the effective data throughput of a single-port RAM alternating read and write operations.

The timing relationships for the dual-port RAM mode are shown in Figure 13.

Note that write operations to RAM are synchronous (edge-triggered); however, data access is asynchronous.

Initializing RAM at FPGA Configuration

Both RAM and ROM implementations in the Spartan/XL families are initialized during device configuration. The initial contents are defined via an INIT attribute or property

attached to the RAM or ROM symbol, as described in the library guide. If not defined, all RAM contents are initialized to zeros, by default.

RAM initialization occurs only during device configuration. The RAM content is not affected by GSR.

More Information on Using RAM Inside CLBs

Three application notes are available from Xilinx that discuss synchronous (edge-triggered) RAM: "Xilinx Edge-Triggered and Dual-Port RAM Capability," "Implementing FIFOs in Xilinx RAM," and "Synchronous and Asynchronous FIFO Designs." All three application notes apply to both the Spartan and the Spartan-XL families.

Fast Carry Logic

Each CLB F-LUT and G-LUT contains dedicated arithmetic logic for the fast generation of carry and borrow signals. This extra output is passed on to the function generator in the adjacent CLB. The carry chain is independent of normal routing resources. (See Figure 15.)

Dedicated fast carry logic greatly increases the efficiency and performance of adders, subtractors, accumulators, comparators and counters. It also opens the door to many new applications involving arithmetic operation, where the previous generations of FPGAs were not fast enough or too inefficient. High-speed address offset calculations in microprocessor or graphics systems, and high-speed addition in digital signal processing are two typical applications.

The two 4-input function generators can be configured as a 2-bit adder with built-in hidden carry that can be expanded to any length. This dedicated carry circuitry is so fast and efficient that conventional speed-up methods like carry generate/propagate are meaningless even at the 16-bit level, and of marginal benefit at the 32-bit level. This fast carry logic is one of the more significant features of the Spartan

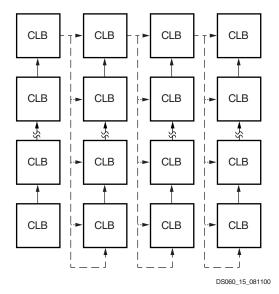


Figure 15: Available Spartan/XL Carry Propagation Paths



and Spartan-XL families, speeding up arithmetic and counting functions.

The carry chain in 5V Spartan devices can run either up or down. At the top and bottom of the columns where there are no CLBs above and below, the carry is propagated to the right. The default is always to propagate up the column, as shown in the figures. The carry chain in Spartan-XL devices can only run up the column, providing even higher speed.

Figure 16, page 18 shows a Spartan/XL FPGA CLB with dedicated fast carry logic. The carry logic shares operand

and control inputs with the function generators. The carry outputs connect to the function generators, where they are combined with the operands to form the sums.

Figure 17, page 19 shows the details of the Spartan/XL FPGA carry logic. This diagram shows the contents of the box labeled "CARRY LOGIC" in Figure 16.

The fast carry logic can be accessed by placing special library symbols, or by using Xilinx Relationally Placed Macros (RPMs) that already include these symbols.



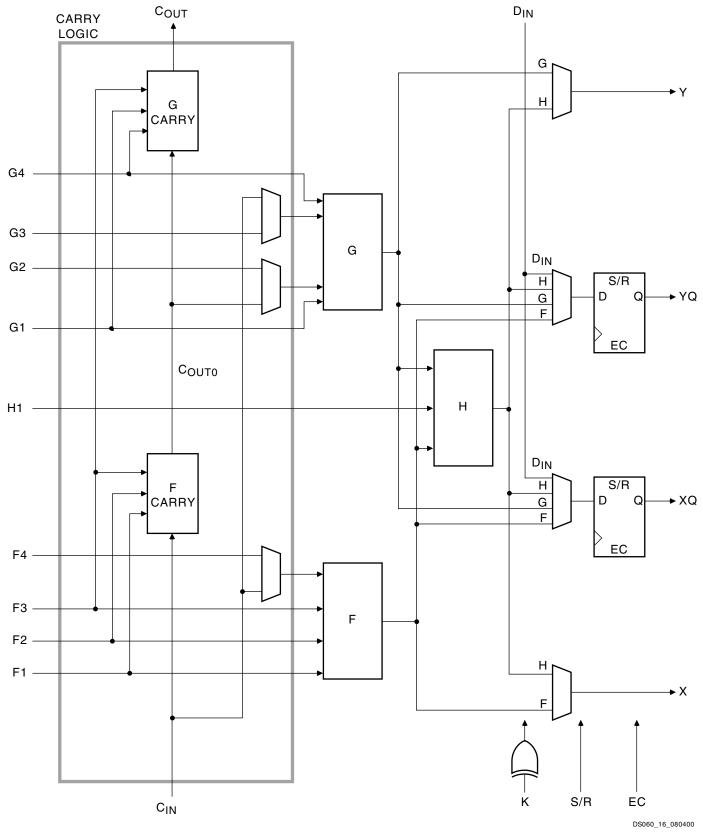


Figure 16: Fast Carry Logic in Spartan/XL CLB



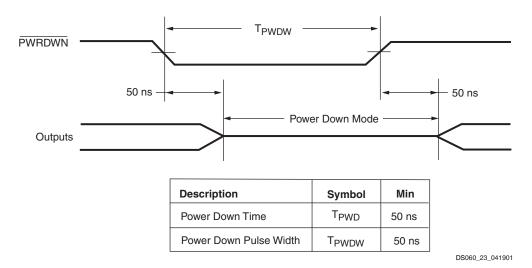


Figure 23: PWRDWN Pulse Timing

Power-down retains the configuration, but loses all data stored in the device flip-flops. All inputs are interpreted as Low, but the internal combinatorial logic is fully functional. Make sure that the combination of all inputs Low and all flip-flops set or reset in your design will not generate internal oscillations, or create permanent bus contention by activating internal bus drivers with conflicting data onto the same long line.

During configuration, the PWRDWN pin must be High. If the Power Down state is entered before or during configuration, the device will restart configuration once the PWRDWN signal is removed. Note that the configuration pins are affected by Power Down and may not reflect their normal function. If there is an external pull-up resistor on the DONE pin, it will be High during Power Down even if the device is not yet configured. Similarly, if PWRDWN is asserted before configuration is completed, the INIT pin will not indicate status information.

Note that the PWRDWN pin is not part of the Boundary Scan chain. Therefore, the Spartan-XL family has a separate set of BSDL files than the 5V Spartan family. Boundary scan logic is not usable during Power Down.

Configuration and Test

Configuration is the process of loading design-specific programming data into one or more FPGAs to define the functional operation of the internal blocks and their interconnections. This is somewhat like loading the command registers of a programmable peripheral chip. Spartan/XL devices use several hundred bits of configuration data per CLB and its associated interconnects. Each configuration bit defines the state of a static memory cell

that controls either a function look-up table bit, a multiplexer input, or an interconnect pass transistor. The Xilinx development system translates the design into a netlist file. It automatically partitions, places and routes the logic and generates the configuration data in PROM format.

Configuration Mode Control

5V Spartan devices have two configuration modes.

- MODE = 1 sets Slave Serial mode
- MODE = 0 sets Master Serial mode

3V Spartan-XL devices have three configuration modes.

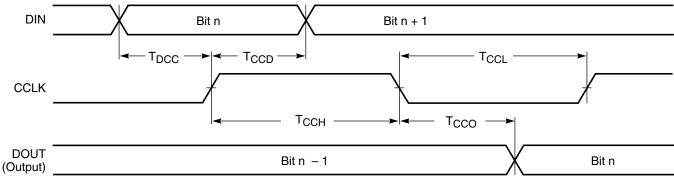
- M1/M0 = 11 sets Slave Serial mode
- M1/M0 = 10 sets Master Serial mode
- M1/M0 = 0X sets Express mode

In addition to these modes, the device can be configured through the Boundary Scan logic (See "Configuration Through the Boundary Scan Pins" on page 37.).

The Mode pins are sampled prior to starting configuration to determine the configuration mode. After configuration, these pin are unused. The Mode pins have a weak pull-up resistor turned on during configuration. With the Mode pins High, Slave Serial mode is selected, which is the most popular configuration mode. Therefore, for the most common configuration mode, the Mode pins can be left unconnected. If the Master Serial mode is desired, the MODE/M0 pin should be connected directly to GND, or through a pull-down resistor of 1 K Ω or less.

During configuration, some of the I/O pins are used temporarily for the configuration process. All pins used during con-





DS060 26 080400

Symbol		Description	Min	Max	Units
T _{DCC}		DIN setup	20	-	ns
T _{CCD}		DIN hold	0	-	ns
T _{CCO}	CCLK	DIN to DOUT	-	30	ns
T _{CCH}	COLK	High time	40	-	ns
T _{CCL}		Low time	40	-	ns
F _{CC}		Frequency	-	12.5	MHz

Notes:

Figure 26: Slave Serial Mode Programming Switching Characteristics

Express Mode (Spartan-XL Family Only)

Express mode is similar to Slave Serial mode, except that data is processed one byte per CCLK cycle instead of one bit per CCLK cycle. An external source is used to drive CCLK, while byte-wide data is loaded directly into the configuration data shift registers (Figure 27). A CCLK frequency of 1 MHz is equivalent to a 8 MHz serial rate, because eight bits of configuration data are loaded per CCLK cycle. Express mode does not support CRC error checking, but does support constant-field error checking. A length count is not used in Express mode.

Express mode must be specified as an option to the development system. The Express mode bitstream is not compatible with the other configuration modes (see Table 16, page 32.) Express mode is selected by a <0X> on the Mode pins (M1, M0).

The first byte of parallel configuration data must be available at the D inputs of the FPGA a short setup time before the second rising CCLK edge. Subsequent data bytes are clocked in on each consecutive rising CCLK edge (Figure 28).

Pseudo Daisy Chain

Multiple devices with different configurations can be configured in a pseudo daisy chain provided that all of the devices

are in Express mode. Concatenated bitstreams are used to configure the chain of Express mode devices so that each device receives a separate header. CCLK pins are tied together and D0-D7 pins are tied together for all devices along the chain. A status signal is passed from DOUT to CS1 of successive devices along the chain. Frame data is accepted only when CS1 is High and the device's configuration memory is not already full. The lead device in the chain has its CS1 input tied High (or floating, since there is an internal pull-up). The status pin DOUT is pulled Low after the header is received, and remains Low until the device's configuration memory is full. DOUT is then pulled High to signal the next device in the chain to accept the next header and configuration data on the D0-D7 bus.

The DONE pins of all devices in the chain should be tied together, with one or more active internal pull-ups. If a large number of devices are included in the chain, deactivate some of the internal pull-ups, since the Low-driving DONE pin of the last device in the chain must sink the current from all pull-ups in the chain. The DONE pull-up is activated by default. It can be deactivated using a development system option.

The requirement that all DONE pins in a daisy chain be wired together applies only to Express mode, and only if all devices in the chain are to become active simultaneously. All Spartan-XL devices in Express mode are synchronized

Configuration must be delayed until the INIT pins of all daisy-chained FPGAs are High.



to the DONE pin. User I/Os for each device become active after the DONE pin for that device goes High. (The exact timing is determined by development system options.) Since the DONE pin is open-drain and does not drive a High value, tying the DONE pins of all devices together prevents all devices in the chain from going High until the last device

in the chain has completed its configuration cycle. If the DONE pin of a device is left unconnected, the device becomes active as soon as that device has been configured. Only devices supporting Express mode can be used to form an Express mode daisy chain.

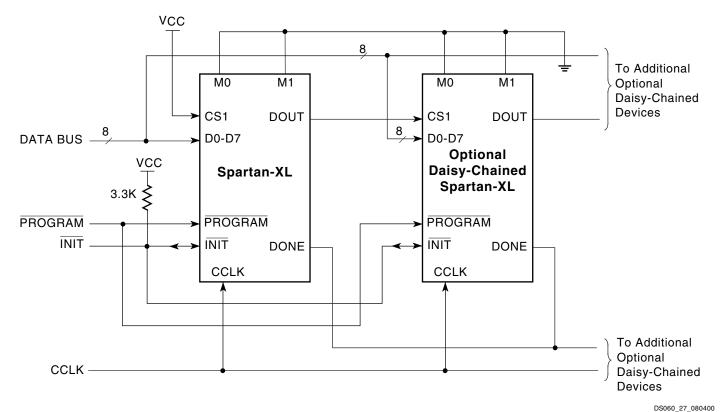
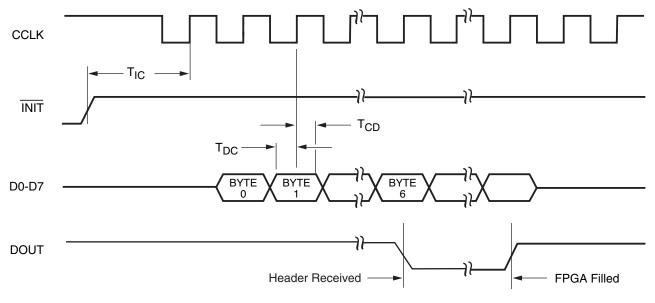


Figure 27: Express Mode Circuit Diagram





DS060_28_080400

Symbol		Description	Min	Max	Units
T _{IC}		INIT (High) setup time	5	-	μs
T _{DC}		D0-D7 setup time	20	-	ns
T _{CD}	CCLK	D0-D7 hold time	0	-	ns
T _{CCH}	COLK	CCLK High time	45	-	ns
T _{CCL}		CCLK Low time	45	-	ns
F _{CC}		CCLK Frequency	-	10	MHz

Notes:

Figure 28: Express Mode Programming Switching Characteristics

Setting CCLK Frequency

In Master mode, CCLK can be generated in either of two frequencies. In the default slow mode, the frequency ranges from 0.5 MHz to 1.25 MHz for Spartan/XL devices. In fast CCLK mode, the frequency ranges from 4 MHz to 10 MHz for Spartan/XL devices. The frequency is changed to fast by an option when running the bitstream generation software.

Data Stream Format

The data stream ("bitstream") format is identical for both serial configuration modes, but different for the Spartan-XL family Express mode. In Express mode, the device becomes active when DONE goes High, therefore no length count is required. Additionally, CRC error checking is not supported in Express mode. The data stream format is shown in Table 16. Bit-serial data is read from left to right.

Express mode data is shown with D0 at the left and D7 at the right.

The configuration data stream begins with a string of eight ones, a preamble code, followed by a 24-bit length count and a separator field of ones (or 24 fill bits, in Spartan-XL family Express mode). This header is followed by the actual configuration data in frames. The length and number of frames depends on the device type (see Table 17). Each frame begins with a start field and ends with an error check. In serial modes, a postamble code is required to signal the end of data for a single device. In all cases, additional start-up bytes of data are required to provide four clocks for the startup sequence at the end of configuration. Long daisy chains require additional start-up bytes to shift the last data through the chain. All start-up bytes are "don't cares".

If not driven by the preceding DOUT, CS1 must remain High until the device is fully configured.



Readback Abort

When the Readback Abort option is selected, a High-to-Low transition on RDBK.TRIG terminates the Readback operation and prepares the logic to accept another trigger.

After an aborted Readback, additional clocks (up to one Readback clock per configuration frame) may be required to re-initialize the control logic. The status of Readback is indicated by the output control net RDBK.RIP. RDBK.RIP is High whenever a readback is in progress.

Clock Select

CCLK is the default clock. However, the user can insert another clock on RDBK.CLK. Readback control and data are clocked on rising edges of RDBK.CLK. If Readback must be inhibited for security reasons, the Readback control nets are simply not connected. RDBK.CLK is located in the lower right chip corner.

Violating the Maximum High and Low Time Specification for the Readback Clock

The Readback clock has a maximum High and Low time specification. In some cases, this specification cannot be

met. For example, if a processor is controlling Readback, an interrupt may force it to stop in the middle of a readback. This necessitates stopping the clock, and thus violating the specification.

The specification is mandatory only on clocking data at the end of a frame prior to the next start bit. The transfer mechanism will load the data to a shift register during the last six clock cycles of the frame, prior to the start bit of the following frame. This loading process is dynamic, and is the source of the maximum High and Low time requirements.

Therefore, the specification only applies to the six clock cycles prior to and including any start bit, including the clocks before the first start bit in the Readback data stream. At other times, the frame data is already in the register and the register is not dynamic. Thus, it can be shifted out just like a regular shift register.

The user must precisely calculate the location of the Readback data relative to the frame. The system must keep track of the position within a data frame, and disable interrupts before frame boundaries. Frame lengths and data formats are listed in Table 16 and Table 17.



Readback Switching Characteristics Guidelines

The following guidelines reflect worst-case values over the recommended operating conditions.

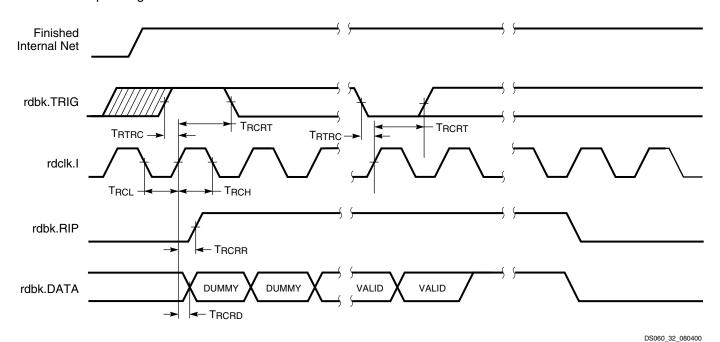


Figure 33: Spartan and Spartan-XL Readback Timing Diagram

Spartan and Spartan-XL Readback Switching Characteristics

Symbol		Description	Min	Max	Units
T _{RTRC}	rdbk.TRIG	rdbk.TRIG setup to initiate and abort Readback	200	-	ns
T _{RCRT}		rdbk.TRIG hold to initiate and abort Readback	50	-	ns
T _{RCRD}	rdclk.l	rdbk.DATA delay	-	250	ns
T _{RCRR}		rdbk.RIP delay	-	250	ns
T _{RCH}		High time	250	500	ns
T _{RCL}		Low time	250	500	ns

- 1. Timing parameters apply to all speed grades.
- 2. If rdbk.TRIG is High prior to Finished, Finished will trigger the first Readback.



Spartan Family CLB Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE

in the Xilinx Development System) and back-annotated to the simulation netlist. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Spartan devices and expressed in nanoseconds unless otherwise noted.

		Speed Grade				
	Description	-	4	-	3	
Symbol		Min	Max	Min	Max	Units
Clocks						
T _{CH}	Clock High time	3.0	-	4.0	-	ns
T_{CL}	Clock Low time	3.0	-	4.0	-	ns
Combina	torial Delays		1	1	1	1
T _{ILO}	F/G inputs to X/Y outputs	-	1.2	-	1.6	ns
T _{IHO}	F/G inputs via H to X/Y outputs	-	2.0	-	2.7	ns
T _{HH1O}	C inputs via H1 via H to X/Y outputs	-	1.7	-	2.2	ns
CLB Fast	Carry Logic		1		1	
T _{OPCY}	Operand inputs (F1, F2, G1, G4) to C _{OUT}	-	1.7	-	2.1	ns
T _{ASCY}	Add/Subtract input (F3) to C _{OUT}	-	2.8	-	3.7	ns
T _{INCY}	Initialization inputs (F1, F3) to C _{OUT}	-	1.2	-	1.4	ns
T _{SUM}	C _{IN} through function generators to X/Y outputs	-	2.0	-	2.6	ns
T _{BYP}	C _{IN} to C _{OUT} , bypass function generators	-	0.5	-	0.6	ns
Sequentia	al Delays					
T _{CKO}	Clock K to Flip-Flop outputs Q	-	2.1	-	2.8	ns
Setup Tin	ne before Clock K					
T _{ICK}	F/G inputs	1.8	-	2.4	-	ns
T _{IHCK}	F/G inputs via H	2.9	-	3.9	-	ns
T _{HH1CK}	C inputs via H1 through H	2.3	-	3.3	-	ns
T _{DICK}	C inputs via DIN	1.3	-	2.0	-	ns
T _{ECCK}	C inputs via EC	2.0	-	2.6	-	ns
T _{RCK}	C inputs via S/R, going Low (inactive)	2.5	-	4.0	-	ns
Hold Time	e after Clock K		1			
	All Hold times, all devices	0.0	-	0.0	-	ns
Set/Reset	Direct					
T _{RPW}	Width (High)	3.0	-	4.0	-	ns
T _{RIO}	Delay from C inputs via S/R, going High to Q	-	3.0	-	4.0	ns
Global Se	et/Reset					
T_{MRW}	Minimum GSR pulse width	11.5	-	13.5	-	ns
T_{MRQ}	Delay from GSR input to any Q	See pa	ge 50 for T _{RI}	RI values per	device.	
F _{TOG}	Toggle Frequency (MHz) (for export control purposes)	-	166	-	125	MHz



Spartan Family Pin-to-Pin Input Parameter Guidelines

All devices are 100% functionally tested. Pin-to-pin timing parameters are derived from measuring external and internal test patterns and are guaranteed over worst-case oper-

ating conditions (supply voltage and junction temperature). Listed below are representative values for typical pin locations and normal clock loading.

Spartan Family Primary and Secondary Setup and Hold

			Speed		
			-4	-3	
Symbol	Description	Device	Min	Min	Units
Input Setup/H	old Times Using Primary Clock and IFF				
T _{PSUF} /T _{PHF}	No Delay	XCS05	1.2 / 1.7	1.8 / 2.5	ns
		XCS10	1.0 / 2.3	1.5 / 3.4	ns
		XCS20	0.8 / 2.7	1.2 / 4.0	ns
		XCS30	0.6 / 3.0	0.9 / 4.5	ns
		XCS40	0.4 / 3.5	0.6 / 5.2	ns
T _{PSU} /T _{PH}	With Delay	XCS05	4.3 / 0.0	6.0 / 0.0	ns
		XCS10	4.3 / 0.0	6.0 / 0.0	ns
		XCS20	4.3 / 0.0	6.0 / 0.0	ns
		XCS30	4.3 / 0.0	6.0 / 0.0	ns
		XCS40	5.3 / 0.0	6.8 / 0.0	ns
Input Setup/H	old Times Using Secondary Clock and IFF				
T_{SSUF}/T_{SHF}	No Delay	XCS05	0.9 / 2.2	1.5 / 3.0	ns
		XCS10	0.7 / 2.8	1.2 / 3.9	ns
		XCS20	0.5 / 3.2	0.9 / 4.5	ns
		XCS30	0.3 / 3.5	0.6 / 5.0	ns
		XCS40	0.1 / 4.0	0.3 / 5.7	ns
T _{SSU} /T _{SH}	With Delay	XCS05	4.0 / 0.0	5.7 / 0.0	ns
		XCS10	4.0 / 0.0	5.7 / 0.0	ns
		XCS20	4.0 / 0.5	5.7 / 0.5	ns
		XCS30	4.0 / 0.5	5.7 / 0.5	ns
		XCS40	5.0 / 0.0	6.5 / 0.0	ns

Setup time is measured with the fastest route and the lightest load. Hold time is measured using the furthest distance and a
reference load of one clock pin per IOB/CLB.

^{2.} IFF = Input Flip-flop or Latch



Spartan-XL Family Detailed Specifications

Definition of Terms

In the following tables, some specifications may be designated as Advance or Preliminary. These terms are defined as follows:

Advance: Initial estimates based on simulation and/or extrapolation from other speed grades, devices, or device families. Values are subject to change. Use as estimates, not for production.

Preliminary: Based on preliminary characterization. Further changes are not expected.

Unmarked: Specifications not identified as either Advance or Preliminary are to be considered Final.

Notwithstanding the definition of the above terms, all specifications are subject to change without notice.

Except for pin-to-pin input and output parameters, the AC parameter delay specifications included in this document are derived from measuring internal test patterns. All specifications are representative of worst-case supply voltage and junction temperature conditions. The parameters included are common to popular designs and typical applications.

Spartan-XL Family Absolute Maximum Ratings⁽¹⁾

Symbol	Description		Value	Units
V _{CC}	Supply voltage relative to GND		-0.5 to 4.0	V
V _{IN}	Input voltage relative to GND	5V Tolerant I/O Checked ^(2, 3)	-0.5 to 5.5	V
		Not 5V Tolerant I/Os ^(4, 5)	-0.5 to $V_{CC} + 0.5$	V
V _{TS}	Voltage applied to 3-state output	5V Tolerant I/O Checked ^(2, 3)	-0.5 to 5.5	V
		Not 5V Tolerant I/Os ^(4, 5)	-0.5 to $V_{CC} + 0.5$	V
T _{STG}	Storage temperature (ambient)		-65 to +150	°C
T _J	Junction temperature	Plastic packages	+125	°C

Notes:

- Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress
 ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions
 is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time may affect device reliability.
- 2. With 5V Tolerant I/Os selected, the Maximum DC overshoot must be limited to either +5.5V or 10 mA and undershoot (below GND) must be limited to either 0.5V or 10 mA, whichever is easier to achieve.
- 3. With 5V Tolerant I/Os selected, the Maximum AC (during transitions) conditions are as follows; the device pins may undershoot to -2.0V or overshoot to + 7.0V, provided this overshoot or undershoot lasts no more than 11 ns with a forcing current no greater than 100 mA.
- 4. Without 5V Tolerant I/Os selected, the Maximum DC overshoot or undershoot must be limited to either 0.5V or 10 mA, whichever is easier to achieve.
- 5. Without 5V Tolerant I/Os selected, the Maximum AC conditions are as follows; the device pins may undershoot to –2.0V or overshoot to V_{CC} + 2.0V, provided this overshoot or undershoot lasts no more than 11 ns with a forcing current no greater than 100 mA.
- 6. For soldering guidelines, see the Package Information on the Xilinx website.

Spartan-XL Family Recommended Operating Conditions

Symbol	Description		Min	Max	Units
V_{CC}	Supply voltage relative to GND, T _J = 0°C to +85°C	Commercial	3.0	3.6	V
	Supply voltage relative to GND, $T_J = -40^{\circ}C$ to $+100^{\circ}C^{(1)}$	Industrial	3.0	3.6	V
V _{IH}	High-level input voltage ⁽²⁾		50% of V _{CC}	5.5	V
V _{IL}	Low-level input voltage ⁽²⁾		0	30% of V _{CC}	V
T _{IN}	Input signal transition time		-	250	ns

- At junction temperatures above those listed as Operating Conditions, all delay parameters increase by 0.35% per °C.
- Input and output measurement threshold is ~50% of V_{CC}.



Spartan-XL Family CLB RAM Synchronous (Edge-Triggered) Write Operation Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE

in the Xilinx Development System) and back-annotated to the simulation netlist. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Spartan-XL devices and are expressed in nanoseconds unless otherwise noted.

		Speed Grade					
			•	-5	-	-4	
Symbol	Single Port RAM	Size ⁽¹⁾	Min	Max	Min	Max	Units
Write Ope	ration						
T _{WCS}	Address write cycle time (clock K period)	16x2	7.7	-	8.4	-	ns
T _{WCTS}		32x1	7.7	-	8.4	-	ns
T _{WPS}	Clock K pulse width (active edge)	16x2	3.1	-	3.6	-	ns
T _{WPTS}		32x1	3.1	-	3.6	-	ns
T _{ASS}	Address setup time before clock K	16x2	1.3	-	1.5	-	ns
T _{ASTS}		32x1	1.5	-	1.7	-	ns
T _{DSS}	DIN setup time before clock K	16x2	1.5	-	1.7	-	ns
T _{DSTS}		32x1	1.8	-	2.1	-	ns
T _{WSS}	WE setup time before clock K	16x2	1.4	-	1.6	-	ns
T _{WSTS}		32x1	1.3	-	1.5	-	ns
	All hold times after clock K	16x2	0.0	-	0.0	-	ns
T _{WOS}	Data valid after clock K	32x1	-	4.5	-	5.3	ns
T _{WOTS}		16x2	-	5.4	-	6.3	ns
Read Ope	ration		11	1			11
T _{RC}	Address read cycle time	16x2	2.6	-	3.1	-	ns
T _{RCT}		32x1	3.8	-	5.5	-	ns
T _{ILO}	Data Valid after address change (no Write	16x2	-	1.0	-	1.1	ns
T _{IHO}	Enable)	32x1	-	1.7	-	2.0	ns
T _{ICK}	Address setup time before clock K	16x2	0.6	-	0.7	-	ns
T _{IHCK}		32x1	1.3	-	1.6	-	ns
Notes:							

Notes:

56

^{1.} Timing for 16 x 1 RAM option is identical to 16 x 2 RAM timing.



Spartan-XL Family Pin-to-Pin Input Parameter Guidelines

All devices are 100% functionally tested. Pin-to-pin timing parameters are derived from measuring external and internal test patterns and are guaranteed over worst-case oper-

ating conditions (supply voltage and junction temperature). Listed below are representative values for typical pin locations and normal clock loading.

Spartan-XL Family Setup and Hold

			Speed Grade		
			-5	-4	
Symbol	Description	Device	Max	Max	Units
Input Setup/H	old Times Using Global Clock and IFF				
T _{SUF} /T _{HF}	No Delay	XCS05XL	1.1/2.0	1.6/2.6	ns
		XCS10XL	1.0/2.2	1.5/2.8	ns
		XCS20XL	0.9/2.4	1.4/3.0	ns
		XCS30XL	0.8/2.6	1.3/3.2	ns
		XCS40XL	0.7/2.8	1.2/3.4	ns
T _{SU} /T _H	Full Delay	XCS05XL	3.9/0.0	5.1/0.0	ns
		XCS10XL	4.1/0.0	5.3/0.0	ns
		XCS20XL	4.3/0.0	5.5/0.0	ns
		XCS30XL	4.5/0.0	5.7/0.0	ns
		XCS40XL	4.7/0.0	5.9/0.0	ns

Notes:

- 1. IFF = Input Flip-Flop or Latch
- 2. Setup time is measured with the fastest route and the lightest load. Hold time is measured using the furthest distance and a reference load of one clock pin per IOB/CLB.

Capacitive Load Factor

Figure 35 shows the relationship between I/O output delay and load capacitance. It allows a user to adjust the specified output delay if the load capacitance is different than 50 pF. For example, if the actual load capacitance is 120 pF, add 2.5 ns to the specified delay. If the load capacitance is 20 pF, subtract 0.8 ns from the specified output delay. Figure 35 is usable over the specified operating conditions of voltage and temperature and is independent of the output slew rate control.

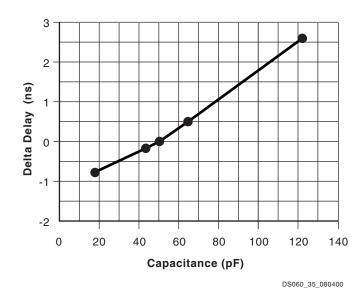


Figure 35: Delay Factor at Various Capacitive Loads



Spartan-XL Family IOB Output Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to

the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values are expressed in nanoseconds unless otherwise noted.

			Speed Grade -5 -4		Grade			
					4			
Symbol	Description	Device	Min	Max	Min	Max	Units	
Propagation	Propagation Delays							
T _{OKPOF}	Clock (OK) to Pad, fast	All devices	-	3.2	-	3.7	ns	
T _{OPF}	Output (O) to Pad, fast	All devices	-	2.5	-	2.9	ns	
T _{TSHZ}	3-state to Pad High-Z (slew-rate independent)	All devices	-	2.8	-	3.3	ns	
T _{TSONF}	3-state to Pad active and valid, fast	All devices	-	2.6	-	3.0	ns	
T _{OFPF}	Output (O) to Pad via Output MUX, fast	All devices	-	3.7	-	4.4	ns	
T _{OKFPF}	Select (OK) to Pad via Output MUX, fast	All devices	-	3.3	-	3.9	ns	
T _{SLOW}	For Output SLOW option add	All devices	-	1.5	-	1.7	ns	
Setup and Hold Times								
T _{OOK}	Output (O) to clock (OK) setup time	All devices	0.5	-	0.5	-	ns	
T _{OKO}	Output (O) to clock (OK) hold time	All devices	0.0	-	0.0	-	ns	
T _{ECOK}	Clock Enable (EC) to clock (OK) setup time	All devices	0.0	-	0.0	-	ns	
T _{OKEC}	Clock Enable (EC) to clock (OK) hold time	All devices	0.1	-	0.2	-	ns	
Global Set/Reset								
T_{MRW}	Minimum GSR pulse width	All devices	10.5	-	11.5	-	ns	
T _{RPO}	Delay from GSR input to any Pad	XCS05XL	-	11.9	-	14.0	ns	
		XCS10XL	-	12.4	-	14.5	ns	
		XCS20XL	-	12.9	-	15.0	ns	
		XCS30XL	-	13.9	-	16.0	ns	
		XCS40XL	-	14.9	-	17.0	ns	

^{1.} Output timing is measured at \sim 50% V_{CC} threshold, with 50 pF external capacitive loads including test fixture. Slew-rate limited output rise/fall times are approximately two times longer than fast output rise/fall times.

^{2.} Voltage levels of unused pads, bonded or unbonded, must be valid logic levels. Each can be configured with the internal pull-up (default) or pull-down resistor, or configured as a driven output, or can be driven from an external source.



XCS20 and XCS20XL Device Pinouts

	CS20 and XCS20XL Device Pinouts				
XCS20/XL Pad Name	VQ100	CS144 ^(2,4)	TQ144	PQ208	Bndry Scan
PROGRAM	P52	M13	P74	P106	-
I/O (D7 ⁽²⁾)	P53	L12	P75	P107	367 ⁽³⁾
I/O,	P54	L13	P76	P108	370 ⁽³⁾
PGCK3 ⁽¹⁾ , GCK5 ⁽²⁾					
I/O		K10	P77	P109	373 ⁽³⁾
1/0	-	K10	P77	P109	373 ⁽³⁾
I/O (D6 ⁽²⁾)	- P55	K11	P79	P110	379 ⁽³⁾
I/O (D6(=/)		K12		P112	382 (3)
	P56	NIS	P80		385 (3)
1/0	-	-	-	P114	
1/0	-	-	-	P115	388 (3)
I/O	-	-	-	P116	391 ⁽³⁾
I/O	-	-	-	P117	394 ⁽³⁾
GND	-	J10	P81	P118	- (2)
I/O	-	J11	P82	P119	397 ⁽³⁾
I/O	-	J12	P83	P120	400 (3)
VCC ⁽²⁾	-	-	-	P121	- (0)
I/O (D5 ⁽²⁾)	P57	J13	P84	P122	403 (3)
I/O	P58	H10	P85	P123	406 ⁽³⁾
I/O	-	-	-	P124	409 (3)
I/O	-	-	-	P125	412 ⁽³⁾
I/O	P59	H11	P86	P126	415 ⁽³⁾
I/O	P60	H12	P87	P127	418 ⁽³⁾
I/O (D4 ⁽²⁾)	P61	H13	P88	P128	421 ⁽³⁾
I/O	P62	G12	P89	P129	424 ⁽³⁾
VCC	P63	G13	P90	P130	-
GND	P64	G11	P91	P131	-
I/O (D3 ⁽²⁾)	P65	G10	P92	P132	427 ⁽³⁾
I/O	P66	F13	P93	P133	430 ⁽³⁾
I/O	P67	F12	P94	P134	433 ⁽³⁾
I/O	-	F11	P95	P135	436 ⁽³⁾
I/O	-	-	-	P136	439 ⁽³⁾
I/O	-	-	-	P137	442 (3)
I/O (D2 ⁽²⁾)	P68	F10	P96	P138	445 ⁽³⁾
I/O	P69	E13	P97	P139	448 ⁽³⁾
VCC ⁽²⁾	-	-	-	P140	-
I/O	_	E12	P98	P141	451 ⁽³⁾
I/O	_	E11	P99	P142	454 ⁽³⁾
GND	-	E10	P100	P143	-
I/O	-	-	-	P145	457 ⁽³⁾
I/O	-	-	-	P146	460 ⁽³⁾
I/O	-	-	-	P147	463 ⁽³⁾
I/O	-	-	-	P148	466 ⁽³⁾
I/O (D1 ⁽²⁾)	P70	D13	P101		
I/O	P71	D12	P102	P150	472 ⁽³⁾
I/O	-	D11	P103	P151	475 ⁽³⁾

XCS20 and XCS20XL Device Pinouts

XCS20/XL Pad Name	VQ100	CS144 ^(2,4)	TQ144	PQ208	Bndry Scan
I/O	-	C13	P104	P152	478 ⁽³⁾
I/O (D0 ⁽²⁾ , DIN)	P72	C12	P105	P153	481 ⁽³⁾
I/O, SGCK4 ⁽¹⁾ , GCK6 ⁽²⁾ (DOUT)	P73	C11	P106	P154	484 ⁽³⁾
CCLK	P74	B13	P107	P155	-
VCC	P75	B12	P108	P156	-
O, TDO	P76	A13	P109	P157	0
GND	P77	A12	P110	P158	-
I/O	P78	B11	P111	P159	2
I/O, PGCK4 ⁽¹⁾ , GCK7 ⁽²⁾	P79	A11	P112	P160	5
I/O	-	D10	P113	P161	8
I/O	-	C10	P114	P162	11
I/O (CS1 ⁽²⁾)	P80	B10	P115	P163	14
I/O	P81	A10	P116	P164	17
I/O	-	D9	P117	P166	20
I/O	-	-	-	P167	23
I/O	-	-	-	P168	26
I/O	-	-	-	P169	29
GND	-	C9	P118	P170	-
I/O	-	B9	P119	P171	32
I/O	-	A9	P120	P172	35
VCC ⁽²⁾	-	-	-	P173	-
I/O	P82	D8	P121	P174	38
I/O	P83	C8	P122	P175	41
I/O	-	-	-	P176	44
I/O	-	-	-	P177	47
I/O	P84	B8	P123	P178	50
I/O	P85	A8	P124	P179	53
I/O	P86	B7	P125	P180	56
I/O	P87	A7	P126	P181	59
GND	P88	C7	P127	P182	-

2/8/00



XCS40 and XCS40XL Device Pinouts

XCS40/XL **Bndry** CS280^(2,5) **Pad Name PQ208 PQ240 BG256** Scan GND GND⁽⁴⁾ GND⁽⁴⁾ P25 P29 VCC P26 P30 VCC⁽⁴⁾ VCC⁽⁴⁾ I/O P31 P27 L2 **K**3 254 I/O P28 P32 L3 K4 257 I/O P33 K5 P29 L4 260 I/O P30 P34 M1 L1 263 I/O P31 P35 M2 L2 266 I/O P32 P36 МЗ L3 269 I/O M4 L4 272 -I/O М1 275 I/O P38 N1 M2 278 I/O P39 N2 МЗ 281 VCC⁽⁴⁾ VCC⁽⁴⁾ VCC P33 P40 I/O P34 P41 Р1 N₁ 284 I/O P35 P42 P2 N2 287 I/O P36 P43 R1 N3 290 I/O P37 P44 P3 N4 293 **GND** P38 P45 GND⁽⁴⁾ GND⁽⁴⁾ I/O P46 T1 P1 296 I/O P39 P47 R3 P2 299 I/O P40 P48 T2 Р3 302 I/O P41 P49 U1 P4 305 I/O P42 P50 Т3 P5 308 I/O P43 P51 U2 R1 311 I/O R2 314 I/O R4 317 --I/O P44 P52 V1 T1 320 I/O P45 P53 T4 T2 323 P46 I/O U3 P54 Т3 326 I/O P47 P55 V2 U1 329 I/O P48 P56 W1 V1 332 I/O, P49 P57 V3 U2 335 SGCK2⁽¹⁾. GCK2 (2) Not P50 P58 W2 V2 338 Connected⁽¹⁾ $M1^{(2)}$ GND GND⁽⁴⁾ GND⁽⁴⁾ P51 P59 $MODE^{(1)}$. P52 P60 Υ1 W1 341 $M0^{(2)}$ VCC P53 P61 VCC(4) VCC⁽⁴⁾ 342(1) Not P54 P62 W3 V3 Connected⁽¹⁾ PWRDWN⁽²⁾ 343 (3) I/O, P55 P63 Y2 W2 PGCK2(1), GCK3⁽²⁾

XCS40 and XCS40XL Device Pinouts

XCS40/XL Pad Name	PQ208	PQ240	BG256	CS280 ^(2,5)	Bndry Scan
I/O (HDC)	P56	P64	W4	W3	346 ⁽³⁾
I/O	P57	P65	V4	T4	349 ⁽³⁾
I/O	P58	P66	U5	U4	352 ⁽³⁾
I/O	P59	P67	Y3	V4	355 ⁽³⁾
I/O (LDC)	P60	P68	Y4	W4	358 ⁽³⁾
I/O	-	-	-	R5	361 ⁽³⁾
I/O	-	-	-	U5	364 ⁽³⁾
I/O	P61	P69	V5	T5	367 ⁽³⁾
I/O	P62	P70	W5	W5	370 ⁽³⁾
I/O	P63	P71	Y5	R6	373 ⁽³⁾
I/O	P64	P72	V6	U6	376 ⁽³⁾
I/O	P65	P73	W6	V6	379 ⁽³⁾
I/O	-	P74	Y6	T6	382 (3)
GND	P66	P75	GND ⁽⁴⁾	GND ⁽⁴⁾	-
I/O	P67	P76	W7	W6	385 (3)
I/O	P68	P77	Y7	U7	388 (3)
I/O	P69	P78	V8	V7	391 ⁽³⁾
I/O	P70	P79	W8	W7	394 ⁽³⁾
VCC	P71	P80	VCC ⁽⁴⁾	VCC ⁽⁴⁾	-
I/O	P72	P81	Y8	W8	397 ⁽³⁾
I/O	P73	P82	U9	U8	400 (3)
I/O	-	-	V9	V8	403 ⁽³⁾
I/O	-	-	W9	T8	406 ⁽³⁾
I/O	-	P84	Y9	W9	409 (3)
I/O	-	P85	W10	V9	412 ⁽³⁾
I/O	P74	P86	V10	U9	415 ⁽³⁾
I/O	P75	P87	Y10	T9	418 ⁽³⁾
I/O	P76	P88	Y11	W10	421 ⁽³⁾
I/O (INIT)	P77	P89	W11	V10	424 ⁽³⁾
VCC	P78	P90	VCC ⁽⁴⁾	VCC ⁽⁴⁾	VCC ⁽⁴⁾
GND	P79	P91	GND ⁽⁴⁾	GND ⁽⁴⁾	-
I/O	P80	P92	V11	T10	427 ⁽³⁾
I/O	P81	P93	U11	R10	430 ⁽³⁾
I/O	P82	P94	Y12	W11	433 ⁽³⁾
I/O	P83	P95	W12	V11	436 ⁽³⁾
I/O	P84	P96	V12	U11	439 ⁽³⁾
I/O	P85	P97	U12	T11	442 ⁽³⁾
I/O	-	-	Y13	W12	445 ⁽³⁾
I/O	-	-	W13	V12	448 ⁽³⁾
I/O	-	P99	V13	U12	451 ⁽³⁾
I/O	-	P100	Y14	T12	454 ⁽³⁾
VCC	P86	P101	VCC ⁽⁴⁾	VCC ⁽⁴⁾	-
I/O	P87	P102	Y15	V13	457 ⁽³⁾
I/O	P88	P103	V14	U13	460 ⁽³⁾
I/O	P89	P104	W15	T13	463 ⁽³⁾



Revision History

The following table shows the revision history for this document.

Date	Version	Description
11/20/98	1.3	Added Spartan-XL specs and Power Down.
01/06/99	1.4	All Spartan-XL -4 specs designated Preliminary with no changes.
03/02/00	1.5	Added CS package, updated Spartan-XL specs to Final.
09/19/01	1.6	Reformatted, updated power specs, clarified configuration information. Removed T_{SOL} soldering information from Absolute Maximum Ratings table. Changed Figure 26: Slave Serial Mode Characteristics: T_{CCH} , T_{CCL} from 45 to 40 ns. Changed Master Mode Configuration Switching Characteristics: T_{CCLK} min. from 80 to 100 ns. Added Total Dist. RAM Bits to Table 1; added Start-Up, page 36 characteristics.
06/27/02	1.7	Clarified Express Mode pseudo daisy chain. Added new Industrial options. Clarified XCS30XL CS280 V _{CC} pinout.
06/26/08	1.8	Noted that PC84, CS144, and CS280 packages, and VQ100 and BG256 packages for XCS30 only, are discontinued by PDN2004-01. Extended description of recommended maximum delay of reconfiguration in Delaying Configuration After Power-Up, page 35. Added reference to Pb-free package options and provided link to Package Specifications, page 81. Updated links.
03/01/13	2.0	The products listed in this data sheet are obsolete. See XCN11010 for further information.